Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/554,263	KIM, SUKYOON
Examiner	Art Unit
David E. Bochna	3679

	SEARCHED				
Class	Subclass	Date	Examiner		
285	307	1/7/2007	DB		
	322				
	323				
	332.1				
	255				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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